

Search Notes

Application/Control No.

10/549,297

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

TAKEHARA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	90	12/21/2006	HN
310	90.5	12/21/2006	HN
310	156.01	12/21/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR